# Regarding the change of names mentioned in the document, such as Mitsubishi Electric and Mitsubishi XX, to Renesas Technology Corp.

The semiconductor operations of Hitachi and Mitsubishi Electric were transferred to Renesas Technology Corporation on April 1st 2003. These operations include microcomputer, logic, analog and discrete devices, and memory chips other than DRAMs (flash memory, SRAMs etc.) Accordingly, although Mitsubishi Electric, Mitsubishi Electric Corporation, Mitsubishi Semiconductors, and other Mitsubishi brand names are mentioned in the document, these names have in fact all been changed to Renesas Technology Corp. Thank you for your understanding. Except for our corporate trademark, logo and corporate statement, no changes whatsoever have been made to the contents of the document, and these changes do not constitute any alteration to the contents of the document itself.

Note : Mitsubishi Electric will continue the business operations of high frequency & optical devices and power devices.

Renesas Technology Corp. Customer Support Dept. April 1, 2003



8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

Those are summarized in the part name table below.

#### DESCRIPTION

The M5M5Y816 is a family of low voltage 8-Mbit static RAMs organized as 524288-words by 16-bit, fabricated by Mitsubishi's high-performance  $0.18\mu m$  CMOS technology.

The M5M5Y816 is suitable for memory applications where a simple interfacing , battery operating and battery backup are the important design objectives.

M5M5Y816WG is packaged in a f-BGA (fine pitch BGA), with the outline of 7.5mm x 8.5mm, ball matrix of 6 x 8 (48ball) and ball pitch of 0.75mm. It gives the best solution for a compaction

of mounting area as well as flexibility of wiring pattern of printed circuit boards.

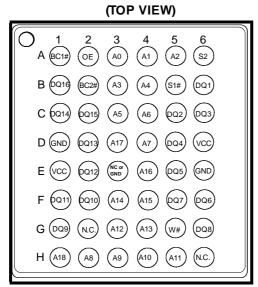
#### FEATURES

- Single 1.65~2.3V power supply
- Small stand-by current: 0.5µA (2.0V, typ.)
- No clocks, No refresh
- Data retention supply voltage =1.3V
- All inputs and outputs are TTL compatible.
- Easy memory expansion by S1#, S2, BC1# and BC2#
- Common Data I/O
- Three-state outputs: OR-tie capability
- OE prevents data contention in the I/O bus
- Process technology: 0.18µm CMOS
- Package: 48ball 7.5mm x 8.5mm f-BGA

Version,		Devee		Stand-by current (µA)						Active	
Operating	Part name	Power	Access time	* Typical		Ratings (max.)			)	current Icc1	
temperature		Supply	max.	25°C	40°C	25°C	40°C	70°C	85°C	(2.3V, max)	
l-version -40 ~ +85°C	(M5M5Y816WG -55HI)	1.65 ~ 2.3V	55ns							30mA	
	M5M5Y816WG -70HI	1.65 ~ 2.3V	70ns	0.5	1	2	4	15	30	(10MHz) 5mA	
	M5M5Y816WG -85HI	1.65 ~ 2.3V	85ns							(1MHz)	

\* Typical parameter indicates the value for the center of distribution at 2.0V, and not 100% tested.

#### **PIN CONFIGURATION**



Pin	Function
A0 ~ A18	Address input
DQ1 ~ DQ16	Data input / output
S1#	Chip select input 1
S2	Chip select input 2
W#	Write control input
OE	Output enable input
BC1#	Lower Byte (DQ1 ~ 8)
BC2#	Upper Byte (DQ9~16)
Vcc	Power supply
GND	Ground supply

Outline: 48F7Q

#### NC: No Connection

\*Don't connect E3 ball to voltage level more than 0V



#### 8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

#### FUNCTION

The M5M5Y 816WG is organized as 524288-words by 16-bit. These devices operate on a single +1.65~2.3V power supply, and are directly TTL compatible to both input and output. Its fully static circuit needs no clocks and no refresh, and makes it useful.

The operation mode are determined by a combination of the device control inputs BC1# , BC2# , S1#, S2 , W# and OE#. Each mode is summarized in the function table.

A write operation is executed whenever the low level W overlaps with the low level BC1# and/or BC2# and the low level S1# and the high level S2. The address(A0~A18) must be set up before the write cycle and must be stable during the entire cycle.

A read operation is executed by setting W# at a high level and OE# at a low level while BC1# and/or BC2# and S1# and S2 are in an active state(S1#=L,S2=H).

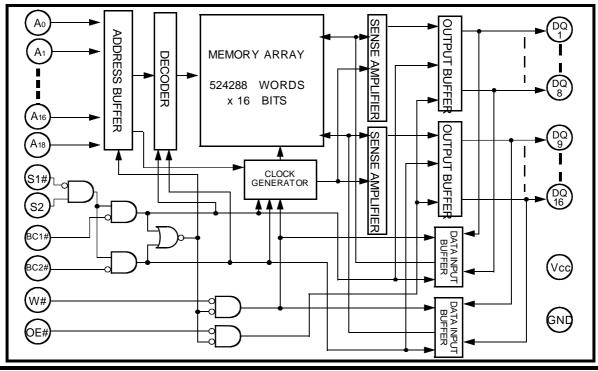
When setting BC1# at the high level and other pins are in an active stage, upper-byte are in a selectable mode in which both reading and writing are enabled, and lower-byte are in a non-selectable mode. And when setting BC2# at a high level and other pins are in an active stage, lower-byte are in a selectable mode and upper-byte are in a non-selectable mode. When setting BC1# and BC2# at a high level or S1# at a high level or S2 at a low level, the chips are in a non-selectable mode in which both reading and writing are disabled. In this mode, the output stage is in a high-impedance state, allowing OR-tie with other chips and memory expansion by BC1#, BC2# and S1#, S2.

The power supply current is reduced as low as  $0.5\mu$ A(25°C, typical), and the memory data can be held at +1.3V power supply, enabling battery back-up operation during power failure or power-down operation in the non-selected mode.

#### FUNCTION TABLE

S1#	S2	BC1#	BC2#	W#	OE#	Mode	DQ1~8	DQ9~16	lcc
Н	L	Х	Х	Х	Х	Non selection	High-Z	High-Z	Standby
L	L	Х	Х	Х	Х	Non selection	High-Z	High-Z	Standby
Н	Н	Х	Х	Х	Х	Non selection	High-Z	High-Z	Standby
Х	Х	Н	Н	Х	Х	Non selection	High-Z	High-Z	Standby
L	Н	L	Н	L	Х	Write	Din	High-Z	Active
L	Н	L	Н	Н	L	Read	Dout	High-Z	Active
L	Н	L	Н	Η	Н		High-Z	High-Z	Active
L	Н	Н	L	L	Х	Write	High-Z	Din	Active
L	Н	Н	L	Н	L	Read	High-Z	Dout	Active
L	Н	Н	L	Η	Н		High-Z	High-Z	Active
L	Н	L	L	L	Х	Write	Din	Din	Active
L	Н	L	L	Н	L	Read	Dout	Dout	Activ e
L	Η	L	L	Н	Н		High-Z	High-Z	Active

note1: "H" and "L" in this table mean VIH and VIL, respectively . note2: "X" in this table should be "H" or "L".



### BLOCK DIAGRAM



### 8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

Symbol	Parameter	Conditions	Ratings	Units
Vcc	Supply voltage	With respect to GND	-0.5* ~ +2.7	
VI	Input voltage	With respect to GND	-0.2* ~ Vcc + 0.2 (max. 2.7V)	V
Vo	Output voltage	With respect to GND	0 ~ Vcc	
Pd	Power dissipation	Ta=25°C	700	mW
Ta	Operating temperature	I-v ersion	- 40 ~ +85	°C
Tstg	Storage temperature		- 65 ~ +150	°C

#### **ABSOLUTE MAXIMUM RATINGS**

\* -0.7V in case of AC (Pulse width  $\leq$  30ns)

### DC ELECTRICAL CHARACTERISTICS

(Vcc=1.65~ 2.3V, unless otherwise noted)

O mile al	Description				Limits		L lus idea
Symbol	Parameter	Conditions		Min	Тур	Max	Units
Vін	High-level input voltage			0.7xVcc		Vcc+0.2	
VIL	Low-lev el input voltage			-0.2 *		0.4	
Vон	High-level output voltage	Iон= -0.1mА		1.3			V
Vol	Low-level output voltage	lo∟=0.1mA			0.2		
h	Input leakage current	Vi=0 ~ Vcc			±1		
lo	Output leakage current	BC1# and BC2#=VIH or S1#=VIH or S2=VIL or OE#			±1	μA	
laat	Active supply current	BC1# and BC2# 0.2V, S1# 0.2V, S2 Vcc-0.2V	f= 10MHz	-	20	30	
Icc1	(AC,MOS level)	Output - open (duty 100%)	f= 1MHz	-	1.5	5	
	Active supply current	BC1# and BC2#=VIL, S1#=VIL, S2=VIH	f= 10MHz	-	20	30	mA
Icc2	(AC,TTL level)	# and BC2#=VIH or S1#=VIH or S2=VIL or OE#=VIH   # and BC2#=0.2V, S1# 0.2V, S2 Vcc-0.2V   # and BC2# 0.2V, S1# 0.2V, S2 Vcc-0.2V   # and BC2# 0.2V or $\geq$ Vcc-0.2V Vcc-0.2V Vcc-0.2V   # and BC2#=VIL, S1#=VIL, S2=VIH Vcc-0.2V Vcc-0.2V   # and BC2#=VIL, S1#=VIL, S2=VIH Vcc-0.2V Vcc-0.2V   It put - open (duty 100%) 0.1 S1# $\geq$ Vcc - 0.2V, Vcc-0.2V,   (a) b1# $\geq$ Vcc - 0.2V, 0.4 Vcc-0.2V, Vcc-0.2V,   (a) b1# and BC2# $\geq$ Vcc - 0.2V 0.4 Vcc-0.2V	f= 1MHz	-	1.5	5	
		(1) S1# ≥ Vcc - 0.2V, S2 > Vcc - 0.2V.	~ +25°C	-	0.5	2	
lcc3	Stand by supply current	other inputs = $0 \sim Vcc$ (2) S2 $\leq 0.2V$ ,	~ +40°C	-	1	4	μA
1005	( AC,MOS level )	other inputs = 0 ~ Vcc (3) BC1# and BC2#≧ Vcc - 0.2V	~ +70°C	-	-	15	μΛ
		S1 $\leq$ 0.2V, S2 $\geq$ Vcc - 0.2V other inputs = 0 ~ Vcc	~ +85°C	-	-	30	
lcc4	Stand by supply current ( AC,TTL level )	BC1# and BC2#=ViH or S1#=ViH or S2= Other inputs= 0 ~ Vcc	VIL	-	-	0.5	mA

\* -0.7V in case of AC (Pulse width ≤ 30ns)

Note 3: Direction for current flowing into IC is indicated as positive (no mark)

Note 4: Typical parameter indicates the value for the center of distribution at 2.0V, and not 100% tested.

#### CAPACITANCE

(Vcc=1.65 ~ 2.3V, unless otherwise noted)

Symbol	Parameter	rameter Conditions		Limits				
	Falameter	Conditions	Min	Тур	Max	Units		
Cı	Input capacitance	VI=GND, VI=25mVrms, f=1MHz			10	nE		
Co	Output capacitance	Vo=GND,Vo=25mVrms, f=1MHz			10	pF		



#### 8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

#### AC ELECTRICAL CHARACTERISTICS (Vcc=1.65 ~ 2.3V, unless otherwise noted) (1) TEST CONDITIONS

			-	
I	Supply voltage	1.65~2.3V		1TTL
	Input pulse	VIH=0.7 x Vcc+0.2V, VIL=0.2V	DQ	
	Input rise time and fall time	5ns	Ŭ	
	Reference level	Voh=Vol=0.9V Transition is measured ±200mV from steady state voltage.(for ten,tdis)		T
	Output loads	Fig.1,CL=30pF		Including scope and
l	Oulput loads	CL=5pF (for ten,tdis)		jig capacitance
2			-	Fig.1 Output load

#### (2) READ CYCLE

			Limits					
Symbol	Parameter	(5	(55HI)		70HI		85HI	
ý		Min	Max	Min	Max	Min	Max	
tcr	Read cycle time	55		70		85		ns
ta(A)	Address access time		55		70		85	ns
ta(S1)	Chip select 1 access time		55		70		85	ns
ta(S2)	Chip select 2 access time		55		70		85	ns
ta(BC1)	Byte control 1 access time		55		70		85	ns
ta(BC2)	Byte control 2 access time		55		70		85	ns
ta(OE)	Output enable access time		30		35		45	ns
t <sub>dis</sub> (S1)	Output disable time after S1# high		20		25		30	ns
tdis(S2)	Output disable time after S2 low		20		25		30	ns
tdis(BC1)	Output disable time after BC1# high		20		25		30	ns
tdis(BC2)	Output disable time after BC2# high		20		25		30	ns
tdis(OE)	Output disable time after OE# high		20		25		30	ns
ten(S1)	Output enable time after S1# low	5		10		10		ns
ten(S2)	Output enable time after S2 high	5		10		10		ns
ten(BC1)	Output enable time after BC1# low	5		5		5		ns
ten(BC2)	Output enable time after BC2# low	5		5		5		ns
t <sub>en</sub> (OE)	Output enable time after OE# low	5		5		5		ns
t∨(A)	Data valid time after address	5		10		10		ns

#### (3) WRITE CYCLE

	Limits     Limits     Limits     Colspan="2">Limits     Parameter   (55HI)   70HI   85HI     Min   Max   Min   Max   Min   Max   Min   Max     Write cycle time   55   70   85   60   1     Write pulse width   45   55   60   1 <t< th=""><th></th></t<>							
Symbol	Parameter	(55HI)   70HI   85HI     Min   Max   Min   Max   Min   M     55   70   85   60	HI	Units				
		Min	Max	Min	Max	Min	Max	
tcw	Write cy cle time	55		70		85		ns
t <sub>w</sub> (W)	Write pulse width	45		55		60		ns
tsu(A)	Address setup time	0		0		0		ns
tsu(A-WH)	Address setup time with respect to W#	50		65		70		ns
tsu(BC1)	Byte control 1 setup time	50		65		70		ns
tsu(BC2)	By te control 2 setup time	50		65		70		ns
tsu(S1)	Chip select 1 setup time	50		65		70		ns
tsu(S2)	Chip select 2 setup time	50		65		70		ns
tsu(D)	Data setup time	25		30		35		ns
th(D)	Data hold time	0		0		0		ns
t <sub>rec</sub> (W)	Write recovery time	0		0		0		ns
tdis(W)	Output disable time from W# low		20		25		30	ns
tdis(OE)	Output disable time from OE# high		20		25		30	ns
ten(W)	Output enable time from W# high	5		5		5		ns
t <sub>en</sub> (OE)	Output enable time from OE# low	5		5		5		ns

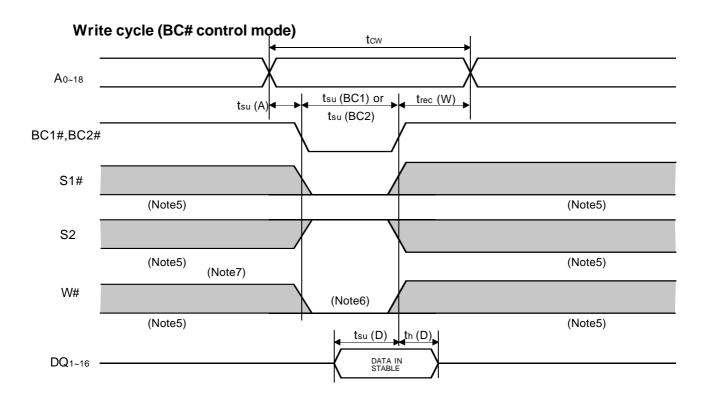


#### 8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM (4)TIMING DIAGRAMS tcr **Read cycle** A0~18 tv(A) ta(A) ta(BC1)or ta(BC2) BC1#,BC2# (Note5) (Note5) tdis (BC1) or tdis (BC1) ta(S1) S1# (Note5) (Note5) tdis (S1) S2 ta(S2) (Note5) (Note5) tdis (S2) ta (OE) OE# (Note5) (Note5) ten (OE) tdis (OE) W# = "H" level ten (BC1) ten (BC2) DQ1~16 -VALID DATA ten (S1) ten (S2) Write cycle (W# control mode) tcw A0~18 tsu (BC1) or tsu(BC2) BC1#,BC2# (Note5) (Note5) tsu (S1) S1# (Note5) (Note5) tsu (S2) S2 (Note5) (Note5) OE# tsu (A-WH) tw (W) tsu (A) 🔺 trec (W) ►tdis (W) W# ten(OE) tdis(OE) ten (W) DATA IN DQ1~16 STABLE tsu (D) th (D)

### M5M5Y816WG (-55HI), -70HI, -85HI



8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM



Note 5: Hatching indicates the state is "don't care".

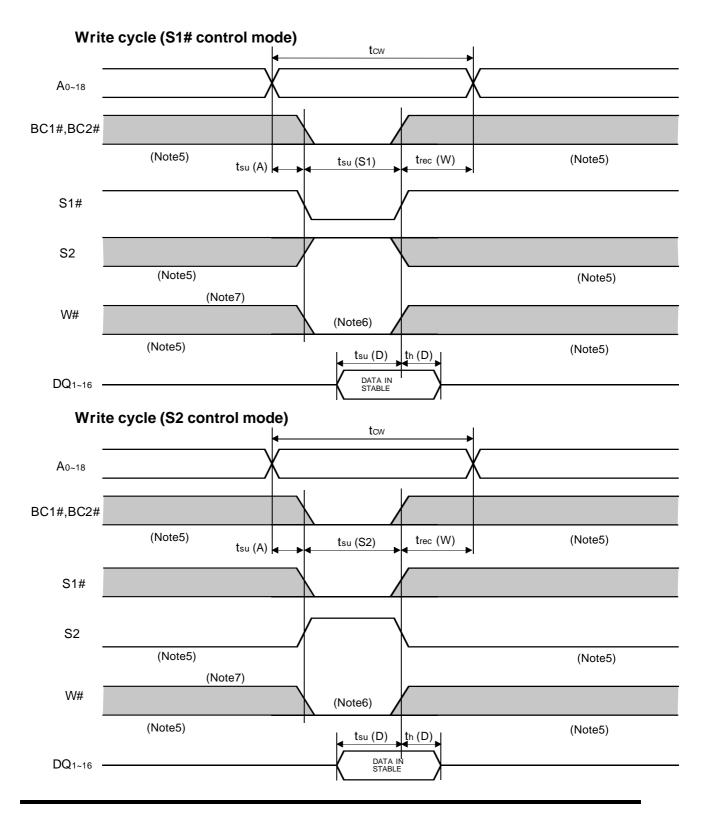
Note 6: A Write occurs during S1# low, S2 high overlaps BC1# and/or BC2# low and W# low.

Note 7: When the falling edge of W# is simultaneously or prior to the falling edge of BC1# and/or BC2# or the falling edge of S1# or rising edge of S2, the outputs are maintained in the high impedance state.

Note 8: Don't apply inverted phase signal externally when DQ pin is in output mode.



8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM





### 8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

#### POWER DOWN CHARACTERISTICS (1) ELECTRICAL CHARACTERISTICS

<b>.</b>					Limits		
Symbol	Parameter	Test conditio	ns	Min	Тур	Max	Units
Vcc (PD)	Power down supply voltage			1.3			V
VI (BC)	Byte control input BC1# &	1.65V≦ Vcc(PD)					
VI (BC)	BC2#	1.3V ≦ Vcc(PD) ≦1.65V			Vcc(PD)		V
VI (S1) Chip		1.65V≦ Vcc(PD)		0.7xVcc			
	Chip select input S1#	1.3V ≦ Vcc(PD) ≦1.65V		Vcc(PD)		V	
VI (S2)	Chip select input S2					0.2	V
		Vcc=1.3V (1) S1# ≥ Vcc - 0.2V,	~ +25°C	-	0.1	1.5	
ICC (PD)	Power down	other inputs = $0 \sim Vcc$ (2) S2 $\leq 0.2V$ ,	~ +40°C	-	0.2	3	
100 (10)	supply current	other inputs = $0 \sim Vcc$ (3) BC1# and BC2# $\geq Vcc - 0.2V$	~ +70°C	-	-	10	μA
		S1# $\leq$ 0.2V, S2 $\geq$ Vcc - 0.2V other inputs = 0 ~ Vcc	~ +85°C	-	-	20	

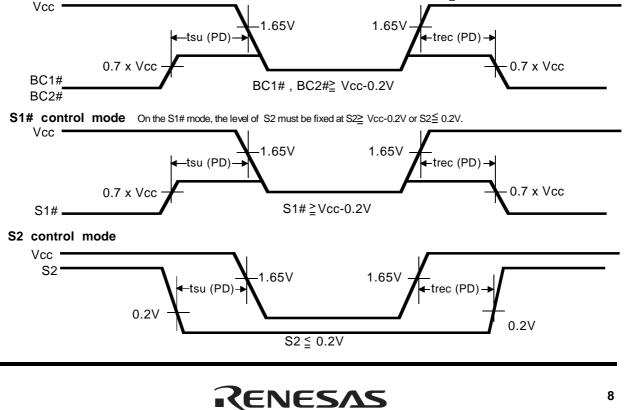
#### (2) TIMING REQUIREMENTS

Note 9: Typical parameter of Icc(PD) indicates the value for the center of distribution at 1.3V, and not 100% tested.

Symbol				1.1		
Symbol	Parameter	Test conditions	Min	Тур	Max	Units
<b>t</b> su (PD)	Power down set up time		0			ns
trec (PD)	Power down recovery time		5			ms

#### (3) TIMING DIAGRAM

BC# control mode On the BC# control mode, the level of S1# and S2 must be fixed at S1#, S2≧Vcc-0.2V or S2≦0.2V



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#### 8388608-BIT (524288-WORD BY 16-BIT) CMOS STATIC RAM

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